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# Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I <sup>2</sup> S, POR, PWM, WDT
Number of I/O	118
Program Memory Size	832KB (832K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	50K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 24x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-144-4
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2387a104f80lrabkfuma1

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# 16/32-Bit

Architecture

# XC2385A, XC2387A

16/32-Bit Single-Chip Microcontroller with 32-Bit Performance XC2000 Family / Base Line

Data Sheet V2.12 2014-06

# Microcontrollers



Table	able 6 Pin Definitions and Functions (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function				
9	P7.3	O0 / I	St/B	Bit 3 of Port 7, General Purpose Input/Output				
	EMUX1	01	St/B	External Analog MUX Control Output 1 (ADC1)				
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output				
	U0C0_DOUT	O3	St/B	USIC0 Channel 0 Shift Data Output				
	CCU62_CCP OS1A	I	St/B	CCU62 Position Input 1				
	TMS_C	IH	St/B	JTAG Test Mode Selection Input If JTAG pos. C is selected during start-up, an internal pull-up device will hold this pin low when nothing is driving it.				
	U0C1_DX0F	I	St/B	USIC0 Channel 1 Shift Data Input				
10	P8.2	O0 / I	St/B	Bit 2 of Port 8, General Purpose Input/Output				
	CCU60_CC6 2	01	St/B	CCU60 Channel 2 Output				
	TxDC1	O2	St/B	CAN Node 1 Transmit Data Output				
	U1C1_DOUT	O3	St/B	USIC1 Channel 1 Shift Data output				
	CCU60_CC6 2INB	I	St/B	CCU60 Channel 2 Input				
11	P7.1	O0 / I	St/B	Bit 1 of Port 7, General Purpose Input/Output				
	EXTCLK	01	St/B	Programmable Clock Signal Output				
	CCU62_CTR APA	I	St/B	CCU62 Emergency Trap Input				
	BRKIN_C	1	St/B	OCDS Break Signal Input				



Tabl	Fable 6         Pin Definitions and Functions (cont'd)						
Pin	Symbol	Ctrl.	Туре	Function			
25	P15.4	I	In/A	Bit 4 of Port 15, General Purpose Input			
	ADC1_CH4	I	In/A	Analog Input Channel 4 for ADC1			
	T6INA	I	In/A	GPT12E Timer T6 Count/Gate Input			
26	P15.5	I	In/A	Bit 5 of Port 15, General Purpose Input			
	ADC1_CH5	I	In/A	Analog Input Channel 5 for ADC1			
	T6EUDA	I	In/A	GPT12E Timer T6 External Up/Down Control Input			
27	P15.6	I	In/A	Bit 6 of Port 15, General Purpose Input			
	ADC1_CH6	I	In/A	Analog Input Channel 6 for ADC1			
28	P15.7	I	In/A	Bit 7 of Port 15, General Purpose Input			
	ADC1_CH7	I	In/A	Analog Input Channel 7 for ADC1			
29	V <sub>AREF1</sub>	-	PS/A	Reference Voltage for A/D Converter ADC1			
30	V <sub>AREF0</sub>	-	PS/A	Reference Voltage for A/D Converter ADC0			
31	V <sub>AGND</sub>	-	PS/A	Reference Ground for A/D Converters ADC0/1			
32	P5.0	I	In/A	Bit 0 of Port 5, General Purpose Input			
	ADC0_CH0	I	In/A	Analog Input Channel 0 for ADC0			
33	P5.1	I	In/A	Bit 1 of Port 5, General Purpose Input			
	ADC0_CH1	I	In/A	Analog Input Channel 1 for ADC0			
34	P5.2	1	In/A	Bit 2 of Port 5, General Purpose Input			
	ADC0_CH2	I	In/A	Analog Input Channel 2 for ADC0			
	TDI_A	I	In/A	JTAG Test Data Input			
35	P5.3	1	In/A	Bit 3 of Port 5, General Purpose Input			
	ADC0_CH3	1	In/A	Analog Input Channel 3 for ADC0			
	T3INA	I	In/A	GPT12E Timer T3 Count/Gate Input			



Table	Table 6         Pin Definitions and Functions (cont'd)						
Pin	Symbol	Ctrl.	Туре	Function			
45	P5.10	I	In/A	Bit 10 of Port 5, General Purpose Input			
	ADC0_CH10	I	In/A	Analog Input Channel 10 for ADC0			
	ADC1_CH10	I	In/A	Analog Input Channel 10 for ADC1			
	BRKIN_A	I	In/A	OCDS Break Signal Input			
	U2C1_DX0F	I	In/A	USIC2 Channel 1 Shift Data Input			
	CCU61_T13 HRA	I	In/A	External Run Control Input for T13 of CCU61			
46	P5.11	I	In/A	Bit 11 of Port 5, General Purpose Input			
	ADC0_CH11	I	In/A	Analog Input Channel 11 for ADC0			
	ADC1_CH11	I	In/A	Analog Input Channel 11 for ADC1			
47	P5.12	I	In/A	Bit 12 of Port 5, General Purpose Input			
	ADC0_CH12	I	In/A	Analog Input Channel 12 for ADC0			
48	P5.13	I	In/A	Bit 13 of Port 5, General Purpose Input			
	ADC0_CH13	I	In/A	Analog Input Channel 13 for ADC0			
	CCU63_T13 HRF	I	In/A	External Run Control Input for T13 of CCU63			
49	P5.14	I	In/A	Bit 14 of Port 5, General Purpose Input			
	ADC0_CH14	I	In/A	Analog Input Channel 14 for ADC0			
50	P5.15	I	In/A	Bit 15 of Port 5, General Purpose Input			
	ADC0_CH15	I	In/A	Analog Input Channel 15 for ADC0			
	RxDC2F	I	In/A	CAN Node 2 Receive Data Input			
51	P2.12	O0 / I	St/B	Bit 12 of Port 2, General Purpose Input/Output			
	U0C0_SELO 4	01	St/B	USIC0 Channel 0 Select/Control 4 Output			
	U0C1_SELO 3	O2	St/B	USIC0 Channel 1 Select/Control 3 Output			
	TXDC2	O3	St/B	CAN Node 2 Transmit Data Output			
	READY	IH	St/B	External Bus Interface READY Input			



Tabl	able 6 Pin Definitions and Functions (cont'd)						
Pin	Symbol	Ctrl.	Туре	Function			
75	P0.0	O0 / I	St/B	Bit 0 of Port 0, General Purpose Input/Output			
	U1C0_DOUT	01	St/B	USIC1 Channel 0 Shift Data Output			
	CCU61_CC6 0	O3	St/B	CCU61 Channel 0 IOutput			
	A0	OH	St/B	External Bus Interface Address Line 0			
	U1C0_DX0A	I	St/B	USIC1 Channel 0 Shift Data Input			
	CCU61_CC6 0INA	I	St/B	CCU61 Channel 0 Input			
	ESR1_11	I	St/B	ESR1 Trigger Input 11			
76	P4.5	00 / 1	St/B	Bit 5 of Port 4, General Purpose Input/Output			
	CC2_CC29	O3 / I	St/B	CAPCOM2 CC29IO Capture Inp./Compare Out.			
	CCU61_CCP OS0A	I	St/B	CCU61 Position Input 0			
_	ESR2_10	Ι	St/B	ESR2 Trigger Input 10			
77	P4.6	O0 / I	St/B	Bit 6 of Port 4, General Purpose Input/Output			
	CC2_CC30	O3 / I	St/B	CAPCOM2 CC30IO Capture Inp./ Compare Out.			
	T4INA	I	St/B	GPT12E Timer T4 Count/Gate Input			
	CCU61_CCP OS1A	I	St/B	CCU61 Position Input 1			
78	P2.7	O0 / I	St/B	Bit 7 of Port 2, General Purpose Input/Output			
	U0C1_SELO 0	01	St/B	USIC0 Channel 1 Select/Control 0 Output			
	U0C0_SELO 1	O2	St/B	USIC0 Channel 0 Select/Control 1 Output			
	CC2_CC20	O3 / I	St/B	CAPCOM2 CC20IO Capture Inp./ Compare Out.			
	A20	ОН	St/B	External Bus Interface Address Line 20			
	U0C1_DX2C	I	St/B	USIC0 Channel 1 Shift Control Input			
	RxDC1C	I	St/B	CAN Node 1 Receive Data Input			
	ESR2_7	1	St/B	ESR2 Trigger Input 7			



Table								
Pin	Symbol	Ctrl.	Туре	Function				
99	P3.4	O0 / I	St/B	Bit 4 of Port 3, General Purpose Input/Output				
	U2C1_SELO 0	01	St/B	USIC2 Channel 1 Select/Control 0 Output				
	U2C0_SELO 1	02	St/B	USIC2 Channel 0 Select/Control 1 Output				
	U0C0_SELO 4	O3	St/B	USIC0 Channel 0 Select/Control 4 Output				
	U2C1_DX2A	I	St/B	USIC2 Channel 1 Shift Control Input				
100	P10.5	O0 / I	St/B	Bit 5 of Port 10, General Purpose Input/Output				
	U0C1_SCLK OUT	01	St/B	USIC0 Channel 1 Shift Clock Output				
	CCU60_COU T62	02	St/B	CCU60 Channel 2 Output				
	U2C0_DOUT	O3	St/B	USIC2 Channel 0 Shift Data Output				
	AD5	OH / IH	St/B	External Bus Interface Address/Data Line 5				
	U0C1_DX1B	I	St/B	USIC0 Channel 1 Shift Clock Input				
101	P3.5	O0 / I	St/B	Bit 5 of Port 3, General Purpose Input/Output				
	U2C1_SCLK OUT	01	St/B	USIC2 Channel 1 Shift Clock Output				
	U2C0_SELO 2	02	St/B	USIC2 Channel 0 Select/Control 2 Output				
	U0C0_SELO 5	O3	St/B	USIC0 Channel 0 Select/Control 5 Output				
	U2C1_DX1A	I	St/B	USIC2 Channel 1 Shift Clock Input				



Table	Fable 6         Pin Definitions and Functions (cont'd)						
Pin	Symbol	Ctrl.	Туре	Function			
134	P9.7	O0 / I	St/B	Bit 7 of Port 9, General Purpose Input/Output			
	CCU62_COU T60	01	St/B	CCU62 Channel 0 Output			
	CCU62_COU T63	02	St/B	CCU62 Channel 3 Output			
	CCU63_CTR APB	I	St/B	CCU63 Emergency Trap Input			
	U2C0_DX1D	I	St/B	USIC2 Channel 0 Shift Clock Input			
	CCU60_CCP OS0B	I	St/B	CCU60 Position Input 0			
135	P1.7	O0 / I	St/B	Bit 7 of Port 1, General Purpose Input/Output			
	CCU62_CC6 0	01	St/B	CCU62 Channel 0 Output			
	U1C1_MCLK OUT	02	St/B	USIC1 Channel 1 Master Clock Output			
	U2C0_SCLK OUT	O3	St/B	USIC2 Channel 0 Shift Clock Output			
	A15	ОН	St/B	External Bus Interface Address Line 15			
	U2C0_DX1C	I	St/B	USIC2 Channel 0 Shift Clock Input			
	CCU62_CC6 0INA	I	St/B	CCU62 Channel 0 Input			
136	XTAL2	0	Sp/M	Crystal Oscillator Amplifier Output			
137	XTAL1	1	Sp/M	<b>Crystal Oscillator Amplifier Input</b> To clock the device from an external source, drive XTAL1, while leaving XTAL2 unconnected. Voltages on XTAL1 must comply to the core supply voltage $V_{\text{DDIM}}$ .			
	ESR2_9	1	St/B	ESR2 Trigger Input 9			



# XC2385A, XC2387A XC2000 Family / Base Line

#### **General Device Information**

Table 6		Pin Definitions and Functions (cont'd)				
Pin	Symbo	I C	trl.	Туре	Function	
20	V <sub>DDPA</sub>	- PS/A		PS/A	<b>Digital Pad Supply Voltage for Domain A</b> Connect decoupling capacitors to adjacent $V_{\text{DDP}}/V_{\text{SS}}$ pin pairs as close as possible to the pins.	
					Note: The A/D_Converters and ports P5, P6 and P15 are fed from supply voltage $V_{DDPA}$ .	
2, 36, 38, 72, 74, 108, 110, 144	V <sub>DDPB</sub>	-		PS/B	<b>Digital Pad Supply Voltage for Domain B</b> Connect decoupling capacitors to adjacent $V_{\text{DDP}}/V_{\text{SS}}$ pin pairs as close as possible to the pins. Note: The on-chip voltage regulators and all ports except P5, P6 and P15 are fed from supply voltage $V_{\text{DDPB}}$ .	
1, 37, 73, 109	V <sub>SS</sub>	-		PS/	<b>Digital Ground</b> All $V_{SS}$ pins must be connected to the ground-line or ground-plane. Note: Also the exposed pad is connected internally to $V_{SS}$ . To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground. For thermal aspects, please refer to the Data Sheet. Board layout examples are given in an application note.	

 To generate the reference clock output for bus timing measurement, f<sub>SYS</sub> must be selected as source for EXTCLK and P2.8 must be selected as output pin. Also the high-speed clock pad must be enabled. This configuration is referred to as reference clock output signal CLKOUT.



### **Functional Description**



#### Figure 7 CCU6 Block Diagram

Timer T12 can work in capture and/or compare mode for its three channels. The modes can also be combined. Timer T13 can work in compare mode only. The multi-channel control unit generates output patterns that can be modulated by timer T12 and/or timer T13. The modulation sources can be selected and combined for signal modulation.



#### **Functional Description**







#### **Functional Description**

# 3.14 MultiCAN Module

The MultiCAN module contains independently operating CAN nodes with Full-CAN functionality which are able to exchange Data and Remote Frames using a gateway function. Transmission and reception of CAN frames is handled in accordance with CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

All CAN nodes share a common set of message objects. Each message object can be individually allocated to one of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

Note: The number of CAN nodes and message objects depends on the selected device type.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to its own message object list and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.



Figure 12 Block Diagram of MultiCAN Module



#### **Functional Description**

# 3.18 Parallel Ports

The XC238xA provides up to 119 I/O lines which are organized into 11 input/output ports and 2 input ports. All port lines are bit-addressable, and all input/output lines can be individually (bit-wise) configured via port control registers. This configuration selects the direction (input/output), push/pull or open-drain operation, activation of pull devices, and edge characteristics (shape) and driver characteristics (output current) of the port drivers. The I/O ports are true bidirectional ports which are switched to high impedance state when configured as inputs. During the internal reset, all port pins are configured as inputs without pull devices active.

All port lines have alternate input or output functions associated with them. These alternate functions can be programmed to be assigned to various port pins to support the best utilization for a given application. For this reason, certain functions appear several times in **Table 10**.

All port lines that are not used for alternate functions may be used as general purpose I/O lines.

Port	Width	I/O	Connected Modules
P0	8	I/O	EBC (A7A0), CCU6, USIC, CAN
P1	8	I/O	EBC (A15A8), CCU6, USIC
P2	14	I/O	EBC (READY, BHE, A23A16, AD15AD13, D15D13), CAN, CC2, GPT12E, USIC, DAP/JTAG
P3	8	I/O	CAN, USIC
P4	8	I/O	EBC (CS3CS0), CC2, CAN, GPT12E, USIC
P5	16	I	Analog Inputs, CCU6, DAP/JTAG, GPT12E, CAN
P6	4	I/O	ADC, CAN, GPT12E
P7	5	I/O	CAN, GPT12E, SCU, DAP/JTAG, CCU6, ADC, USIC
P8	7	I/O	CCU6, DAP/JTAG, USIC
P9	8	I/O	CCU6, DAP/JTAG, CAN
P10	16	I/O	EBC (ALE, RD, WR, AD12AD0, D12D0), CCU6, USIC, DAP/JTAG, CAN
P11	6	I/O	CCU6, USIC, CAN
P15	8	Ι	Analog Inputs, GPT12E

#### Table 10Summary of the XC238xA's Ports



# 4.1.2 Operating Conditions

The following operating conditions must not be exceeded to ensure correct operation of the XC238xA. All parameters specified in the following sections refer to these operating conditions, unless otherwise noticed.

Note: Typical parameter values refer to room temperature and nominal supply voltage, minimum/maximum parameter values also include conditions of minimum/maximum temperature and minimum/maximum supply voltage. Additional details are described where applicable.

Parameter	Symbol		Values		Unit	Note /
		Min.	Тур.	Max.		Test Condition
Voltage Regulator Buffer Capacitance for DMP_M	$\begin{array}{c} C_{\rm EVRM} \\ {\rm SR} \end{array}$	1.0	-	4.7	μF	1)
Voltage Regulator Buffer Capacitance for DMP_1	$C_{\rm EVR1}$ SR	0.47	-	2.2	μF	1)2)
External Load Capacitance	$C_{L} \operatorname{SR}$	-	20 <sup>3)</sup>	-	pF	pin out driver= default 4)
System frequency	$f_{\rm SYS}{ m SR}$	-	-	100	MHz	5)
Overload current for analog inputs <sup>6)</sup>	$I_{\rm OVA}{\rm SR}$	-2	-	5	mA	not subject to production test
Overload current for digital inputs <sup>6)</sup>	$I_{\rm OVD}{\rm SR}$	-5	-	5	mA	not subject to production test
Overload current coupling factor for analog inputs <sup>7)</sup>	K <sub>OVA</sub> CC	-	2.5 x 10⁻⁴	1.5 x 10 <sup>-3</sup>	-	I <sub>OV</sub> < 0 mA; not subject to production test
		-	1.0 x 10 <sup>-6</sup>	1.0 x 10 <sup>-4</sup>	-	I <sub>OV</sub> > 0 mA; not subject to production test
Overload current coupling factor for digital I/O pins	K <sub>OVD</sub> CC	_	1.0 x 10 <sup>-2</sup>	3.0 x 10 <sup>-2</sup>		I <sub>OV</sub> < 0 mA; not subject to production test
		-	1.0 x 10 <sup>-4</sup>	5.0 x 10 <sup>-3</sup>		<i>I</i> <sub>OV</sub> > 0 mA; not subject to production test

# Table 13 Operating Conditions



Table 23	Flash	Parameters (	(cont'd)

Parameter	Symbol		Values		Unit	Note /
		Min.	Тур.	Max.		Test Condition
Number of erase cycles	N <sub>Er</sub> SR	-	-	15 000	cycle s	$t_{RET} \ge 5$ years; Valid for up to 64 user- selected sectors (data storage)
		-	-	1 000	cycle s	$t_{RET} \ge 20$ years

 All Flash module(s) can be erased/programmed while code is executed and/or data is read from only one Flash module or from PSRAM. The Flash module that delivers code/data can, of course, not be erased/programmed.

 Flash module 3 can be erased/programmed while code is executed and/or data is read from any other Flash module.

3) Value of IMB\_IMBCTRL.WSFLASH.

4) Programming and erase times depend on the internal Flash clock source. The control state machine needs a few system clock cycles. This increases the stated durations noticably only at extremely low system clock frequencies.

Access to the XC238xA Flash modules is controlled by the IMB. Built-in prefetch mechanisms optimize the performance for sequential access.

Flash access waitstates only affect non-sequential access. Due to prefetch mechanisms, the performance for sequential access (depending on the software structure) is only partially influenced by waitstates.



# **Direct Drive**

When direct drive operation is selected (SYSCON0.CLKSEL =  $11_B$ ), the system clock is derived directly from the input clock signal CLKIN1:

 $f_{\text{SYS}} = f_{\text{IN}}$ .

The frequency of  $f_{SYS}$  is the same as the frequency of  $f_{IN}$ . In this case the high and low times of  $f_{SYS}$  are determined by the duty cycle of the input clock  $f_{IN}$ .

Selecting Bypass Operation from the XTAL1<sup>1)</sup> input and using a divider factor of 1 results in a similar configuration.

#### **Prescaler Operation**

When prescaler operation is selected (SYSCON0.CLKSEL =  $10_B$ , PLLCON0.VCOBY =  $1_B$ ), the system clock is derived either from the crystal oscillator (input clock signal XTAL1) or from the internal clock source through the output prescaler K1 (= K1DIV+1):

 $f_{\text{SYS}} = f_{\text{OSC}} / \text{K1}.$ 

If a divider factor of 1 is selected, the frequency of  $f_{\rm SYS}$  equals the frequency of  $f_{\rm OSC}$ . In this case the high and low times of  $f_{\rm SYS}$  are determined by the duty cycle of the input clock  $f_{\rm OSC}$  (external or internal).

The lowest system clock frequency results from selecting the maximum value for the divider factor K1:

 $f_{\rm SYS} = f_{\rm OSC} / 1024.$ 

# 4.6.2.1 Phase Locked Loop (PLL)

When PLL operation is selected (SYSCON0.CLKSEL =  $10_B$ , PLLCON0.VCOBY =  $0_B$ ), the on-chip phase locked loop is enabled and provides the system clock. The PLL multiplies the input frequency by the factor **F** ( $f_{SYS} = f_{IN} \times F$ ).

**F** is calculated from the input divider P (= PDIV+1), the multiplication factor N (= NDIV+1), and the output divider K2 (= K2DIV+1):

 $(F = N / (P \times K2)).$ 

The input clock can be derived either from an external source at XTAL1 or from the onchip clock source.

The PLL circuit synchronizes the system clock to the input clock. This synchronization is performed smoothly so that the system clock frequency does not change abruptly.

Adjustment to the input clock continuously changes the frequency of  $f_{\text{SYS}}$  so that it is locked to  $f_{\text{IN}}$ . The slight variation causes a jitter of  $f_{\text{SYS}}$  which in turn affects the duration of individual TCSs.

<sup>1)</sup> Voltages on XTAL1 must comply to the core supply voltage  $V_{\text{DDIM}}$ .





Figure 28 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.



#### Debug via JTAG

The following parameters are applicable for communication through the JTAG debug interface. The JTAG module is fully compliant with IEEE1149.1-2000.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply;  $C_1 = 20 \text{ pF}$ .

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
TCK clock period	$t_1$ SR	50 <sup>1)</sup>	-	-	ns	2)
TCK high time	$t_2$ SR	16	-	-	ns	
TCK low time	t <sub>3</sub> SR	16	-	-	ns	
TCK clock rise time	t <sub>4</sub> SR	-	-	8	ns	
TCK clock fall time	t <sub>5</sub> SR	-	-	8	ns	
TDI/TMS setup to TCK rising edge	t <sub>6</sub> SR	6	-	-	ns	
TDI/TMS hold after TCK rising edge	t <sub>7</sub> SR	6	-	-	ns	
TDO valid from TCK falling edge (propagation delay) <sup>3)</sup>	t <sub>8</sub> CC	-	25	29	ns	
TDO high impedance to valid output from TCK falling edge <sup>4)3)</sup>	<i>t</i> <sub>9</sub> CC	-	25	29	ns	
TDO valid output to high impedance from TCK falling edge <sup>3)</sup>	<i>t</i> <sub>10</sub> CC	-	25	29	ns	
TDO hold after TCK falling edge <sup>3)</sup>	<i>t</i> <sub>18</sub> CC	5	_	_	ns	

#### Table 40JTAG Interface Timing for Upper Voltage Range

1) The debug interface cannot operate faster than the overall system, therefore  $t_1 \ge t_{SYS}$ .

2) Under typical conditions, the interface can operate at transfer rates up to 20 MHz.

3) The falling edge on TCK is used to generate the TDO timing.

4) The setup time for TDO is given implicitly by the TCK cycle time.



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Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
TCK clock period	t <sub>1</sub> SR	50 <sup>1)</sup>	-	_	ns	2)
TCK high time	$t_2$ SR	16	-	-	ns	
TCK low time	t <sub>3</sub> SR	16	-	-	ns	
TCK clock rise time	$t_4$ SR	-	-	8	ns	
TCK clock fall time	$t_5 \mathrm{SR}$	-	-	8	ns	
TDI/TMS setup to TCK rising edge	t <sub>6</sub> SR	6	-	-	ns	
TDI/TMS hold after TCK rising edge	t <sub>7</sub> SR	6	-	-	ns	
TDO valid from TCK falling edge (propagation delay) <sup>3)</sup>	t <sub>8</sub> CC	-	32	36	ns	
TDO high impedance to valid output from TCK falling edge <sup>4)3)</sup>	t <sub>9</sub> CC	-	32	36	ns	
TDO valid output to high impedance from TCK falling edge <sup>3)</sup>	<i>t</i> <sub>10</sub> CC	-	32	36	ns	
TDO hold after TCK falling edge <sup>3)</sup>	<i>t</i> <sub>18</sub> CC	5	-	-	ns	

#### Table 41 JTAG Interface Timing for Lower Voltage Range

1) The debug interface cannot operate faster than the overall system, therefore  $t_1 \ge t_{SYS}$ .

2) Under typical conditions, the interface can operate at transfer rates up to 20 MHz.

3) The falling edge on TCK is used to generate the TDO timing.

4) The setup time for TDO is given implicitly by the TCK cycle time.



#### Package and Reliability

# 5 Package and Reliability

The XC2000 Family devices use the package type PG-LQFP (Plastic Green - Low Profile Quad Flat Package). The following specifications must be regarded to ensure proper integration of the XC238xA in its target environment.

# 5.1 Packaging

These parameters specify the packaging rather than the silicon.

Parameter	Symbol	Lin	nit Values	Unit	Notes
		Min.	Max.		
Exposed Pad Dimension	$E \mathbf{x} \times E \mathbf{y}$	-	6.5  imes 6.5	mm	-
Power Dissipation	$P_{DISS}$	-	1.0	W	-
Thermal resistance	$R_{\Theta JA}$	-	43	K/W	No thermal via <sup>1)</sup>
Junction-Ambient			34	K/W	4-layer, no pad <sup>2)</sup>
			21	K/W	4-layer, pad <sup>3)</sup>

Table 42 Package Parameters (PG-LQFP-144-13/-23)

1) Device mounted on a 2-layer JEDEC board (according to JESD 51-3) or a 4-layer board without thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad soldered to the board.

Note: To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground, independent of the thermal requirements. Board layout examples are given in an application note.

#### Package Compatibility Considerations

The XC238xA is a member of the XC2000 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the Exposed Pad (if present) may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.



#### Package and Reliability

# 5.3 Quality Declarations

The operation lifetime of the XC238xA depends on the applied temperature profile in the application. For a typical example, please refer to **Table 44**; for other profiles, please contact your Infineon counterpart to calculate the specific lifetime within your application.

#### Table 43Quality Parameters

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
Operation lifetime	t <sub>OP</sub> CC	-	_	20	а	See Table 44 and Table 45
ESD susceptibility according to Human Body Model (HBM)	$V_{\rm HBM}$ SR	-	-	2 000	V	EIA/JESD22- A114-B
Moisture sensitivity level	MSL CC	-	-	3	_	JEDEC J-STD-020C

#### Table 44 Typical Usage Temperature Profile

Operating Time (Sum = 20 years)	Operating Temperat.	Notes
1 200 h	<i>T</i> <sub>J</sub> = 150°C	Normal operation
3 600 h	<i>T</i> <sub>J</sub> = 125°C	Normal operation
7 200 h	<i>T</i> <sub>J</sub> = 110°C	Normal operation
12 000 h	<i>T</i> <sub>J</sub> = 100°C	Normal operation
7 × 21 600 h	T <sub>J</sub> = 010°C,, 6070°C	Power reduction

#### Table 45 Long Time Storage Temperature Profile

Operating Time (Sum = 20 years)	Operating Temperat.	Notes
2 000 h	<i>T</i> <sub>J</sub> = 150°C	Normal operation
16 000 h	<i>T</i> <sub>J</sub> = 125°C	Normal operation
6 000 h	<i>T</i> <sub>J</sub> = 110°C	Normal operation
151 200 h	$T_{\rm J} \le 150^{\circ}{ m C}$	No operation